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## **AMENDMENTS TO THE CLAIMS**

This listing of claims will replace all prior versions, and listings, of claims in the application.

## **Listing of Claims**:

Claim 1 (Canceled without prejudice or disclaimer).

2. (Currently Amended) The semiconductor integrated circuit according to claim 1 comprising:

a nonvolatile memory to store address information indicating a relationship between an address of a first memory space and an address of a second memory space:

a plurality of functional modules each to have an address in the second memory space; and

a bus control circuit,

wherein the bus control circuit receives a first address in the first memory space and translates the first address into a second address in the second memory space using the address information and access is made to a functional module having the second address among the plurality of functional modules, further comprising:

a bus; and

a switching circuit to control a connection between the plurality of functional modules and the bus,

wherein:

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the nonvolatile memory stores connect/disconnect information for the plurality of functional modules; and

the switching circuit selects a functional module to be connected with the bus according to the connect/disconnect information.

- 3. (Currently Amended) The semiconductor integrated circuit according to elaim 1, claim 2, wherein the address information is stored in the nonvolatile memory when a probing test is conducted on the semiconductor integrated circuit.
- 4. (Original)The semiconductor integrated circuit according to claim 2, wherein the connect/disconnect information is stored in the nonvolatile memory when a probing test is conducted on the semiconductor integrated circuit.